

Karhunen-Loève Expansion Analysis of Uncertainties in Cloud Microphysical Property Retrievals

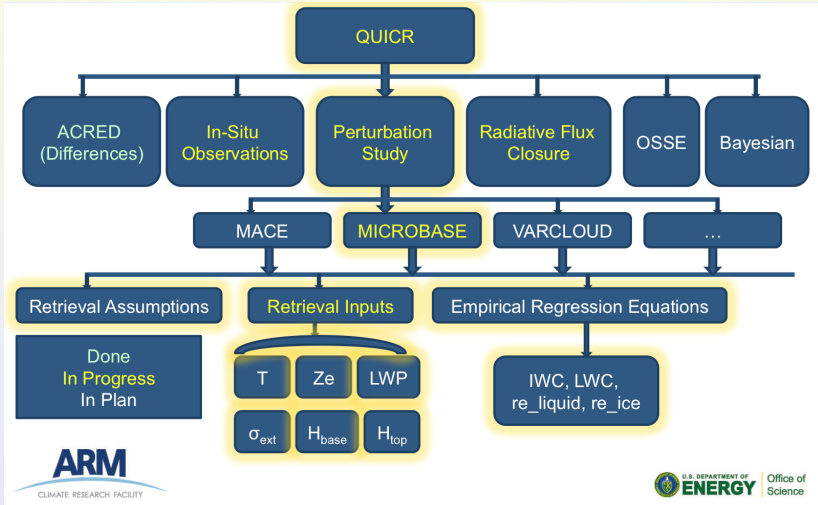
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Chitra Sivaraman, Timothy Shippert, and Charles Tong*

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Overview



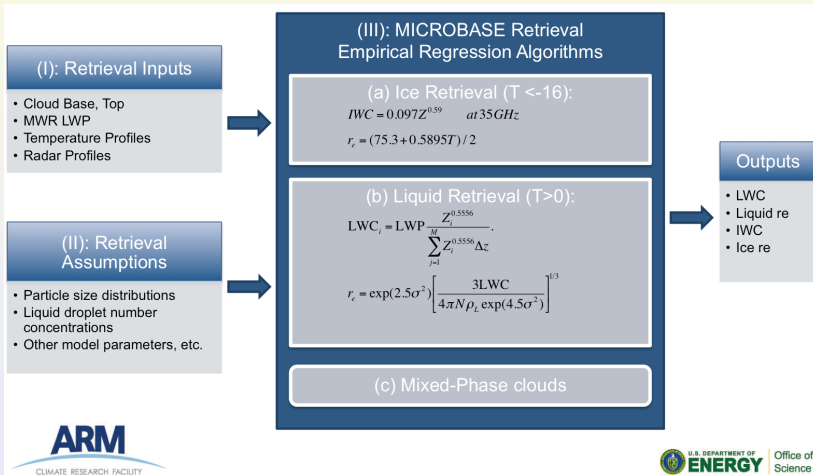
QUICR mission statement

*“to develop a **methodology** for ... quantifying uncertainties in ... ARM cloud retrievals ... in support of both **retrieval algorithm** improvement and **cloud modeling** study”*

Questions

- What are the **vertically-resolved** cloud retrieval uncertainties on model temporal resolution (**~30 min**)?
- How large are the uncertainties from individual sources (e.g., **instrument noise, parameters, sampling**, etc)?

MICROBASE algorithm



Perturb MICROBASE (w/ PSUADE). HOW?

Problem Solving environment for Uncertainty Analysis and Design Exploration

- “Curse of dimensionality” in the stochastic input space
 - $315(T)+512(Ze)+1(LWP)=828$ input layers prohibit large random sampling. **Correlated?**
- Parameterization of inputs by random variables
- Sampling input random variables (i.e., PDF)
 - Assumption of probability distributions (e.g., uniform) disagrees with observations.
- Current MICROBASE frame work **CANNOT** do parallel runs. Large number runs are infeasible.
 - 50,000 times of perturbations per day require 50,000 min $\approx$ **35 days & 11 TB** disk space

Karhunen-Loève (KL) + Central limit theorem (CLT)

- KLE reduces dimensions (**828 to 14 modes**) and extracts **uncorrelated, independent** input random variables.
- CLT shows that **sample mean** of random input variables approximately follows **normal distribution** ($n \rightarrow \infty$).

The central mean subtracted KLE w/ observation noise:

$$\overline{\mathcal{X}} = \sum_{i=1}^r U_i \frac{S_i}{\sqrt{m}} \sqrt{1 + \left(\frac{\sigma_0}{\frac{S_i}{\sqrt{m}}} \right)^2} \frac{z_i}{\sqrt{m}}$$

$z_i \sim N(0, 1)$, $noise_i \sim N(0, \sigma_0^2)$, where z_i and $noise_i$ are *i.i.d.*

Uniform distribution is used for parameter uncertainties.

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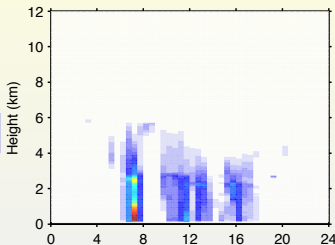
The perturbation range follows Zhao et al. 2013, submitted to JGR.

Input	T (K)	Ze (dbZ)	LWP (%)
Range	0.5	0.5	15

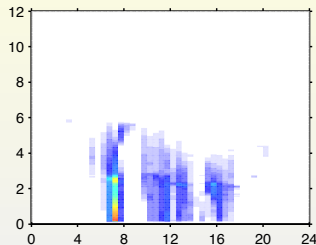
Pars	a (g/m ³)	d (μm °C)	g	σ	N (cm ⁻³)
Range	0.03–0.22	0.2311–0.8211	0.5–0.6	0.2–0.6	10–350

0.5-hr averages of LWC & IWC at SGP on 2006/05/10

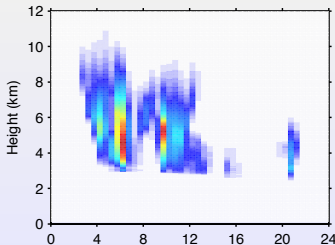
Raw LWC



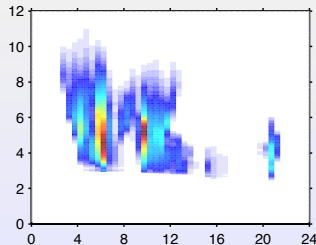
UQ LWC



Raw IWC



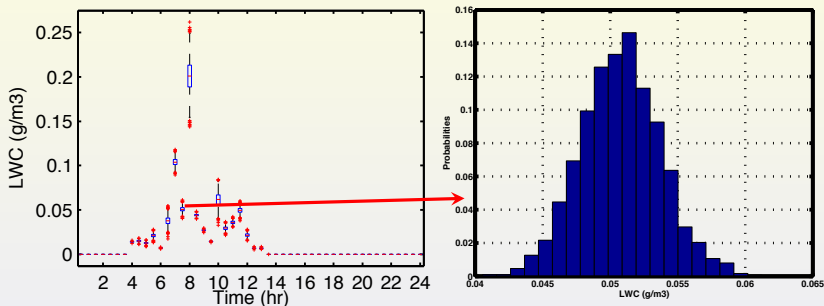
UQ IWC



Time (hr)

0 0.2 0.4 0.6 g/m³

PDF of LWC at 5 km on 2006/05/10

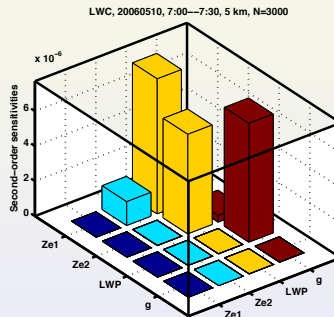
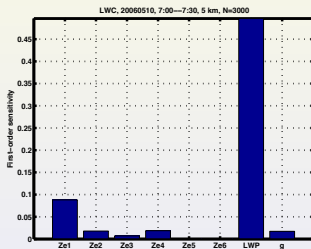


- Perturbing MICROBASE inputs by adding instrument noise and parameter uncertainties yields height-time probability distribution functions (PDFs) for retrieval products.
- These observation-based PDFs are better a priori for other UQ studies (e.g., MCMC).

Sensitivities of LWC to input random variables

$$LWC = LWP \frac{Z_e^g}{\sum_{j=1}^M Z_e^g \Delta z}$$

PSUADE



- Allows attributing uncertainties to individual input variables.
- Provides directions to improve instruments & obs strategies.

Summary of MICROBASE UQ

Source	Type	Approach implemented by PSUADE	Mathematical Theorem
Retrieval Inputs	Inputs Data Variability and Noise	Perturb principal modes	Principal Component Analysis or Karhunen-Loeve expansion
		Sampling distribution of sample mean	Central Limit Theorem
Parameters in Retrieval Assumptions and Algorithms	Parametric Uncertainties	Alertory variability	Uniform/Triangular Distribution Assumption
		Epistemic uncertainty quantification	Evidence Theory
Equations of Retrieval Algorithms	Model-Form Uncertainties	Model error/ discrepancy analysis	Validation, Verification and Uncertainty Quantification

Thank you!